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Application/Control No.	Applicant(s)/Patent under Reexamination
10/084,241	HAO ET AL.
Examiner	Art Unit
Jia W. Lu	2634

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Class	Subclass	Date	Examiner
375	141	6/9/2005	JL
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INT	ERFERENC	CE SEARCH	ED
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375	141	6/9/2005	JL
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SEARCH NO (INCLUDING SEARCH		<b>)</b> ,
	DATE	EXMR
US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	6/9/2005	JL
INVENTORSHIP	6/9/2005	JL
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